

10/520 445  
DT15 Rec' CT/PTO 06 JAN 2005  
PATENT  
450100-04677

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Applicants: **Takuji HIMENO et al.**

International Application No.: **PCT/JP03/08432**

International Filing Date: **July 2, 2003**

For: **IMAGE DATA PROCESSING APPARATUS AND  
METHOD**

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Enclosed are copies of the publications, which were cited in the International Search Report of International Application No. PCT/JP03/08432. Also enclosed is a copy of Form PTO-1449 and the International Search Report.

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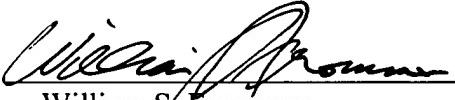
**REMARKS**

Entry of this Information Disclosure Statement and an early examination on the merits are respectfully solicited.

Please charge any additional fees to Deposit Account No. 50-0320.

Respectfully submitted,

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Enclosures

Based on Form PTO-1449 (3/90)  LIST OF REFERENCES CITED BY APPLICANT (Use several sheets if necessary)	ATTY. DOCKET NO. 450100-04677	SERIAL NO. 10/1520445 Filed Concurrently Herewith
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	AM	JP 2000-92448	03/31/00	Japan			
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